

Abstracts

Experimental Assessment of Bilateral Fin-Line Impedance for Device Matching

H.A. Willing and B.E. Spielman. "Experimental Assessment of Bilateral Fin-Line Impedance for Device Matching." 1981 MTT-S International Microwave Symposium Digest 81.1 (1981 [MWSYM]): 105-107.

This paper describes the results of an experimental investigation of bilateral fin-line impedance characteristics for matching to small-chip devices. The results from two different experimental approaches are presented and compared with computed results.

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